



<b>Search Notes</b>  	Application/Control No.  10671633	Applicant(s)/Patent Under Reexamination  NAKAI ET AL.
	Examiner DINH, DUC Q	Art Unit 2629


Notes	Date	Examiner
EAST SEARCH, SEE ATTACH	6/8/2006	DD

U.S. Patent and Trademark Office	Part of Paper No.:
----------------------------------	--------------------

<b>Interference Searched</b>  	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10671633	NAKAI ET AL.
	Examiner DINH, DUC Q	Art Unit 2629

Class	SubClass	Date	Examiner
348	14.7, 52,383		
455	566	6/7/2006	DD

U.S. Patent and Trademark Office	Part of Paper No.:
----------------------------------	--------------------

<p align="center"><b>Searched</b></p> 	<p>Application/Control No.</p> <p>10671633</p>	<p>Applicant(s)/Patent Under Reexamination</p> <p>NAKAI ET AL.</p>
	<p>Examiner</p> <p>DINH, DUC Q</p>	<p>Art Unit</p> <p>2629</p>

Class	SubClass	Date	Examiner
345	1.1-3.3,169,690,204		
	87-100,541,545	06/07/06	DD

U.S. Patent and Trademark Office	Part of Paper No.:
----------------------------------	--------------------